N-Channel Enhancement Mode MOSFET

Description

The NVMFS5C670NLWFAFT3G uses advanced trench technology to provide excellent RDS(ON), low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

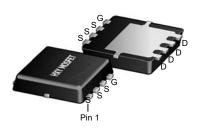
 $V_{DS} = 60V I_D = 80 A$ $R_{DS(ON)} < 7m\Omega @ V_{GS} = 10V$

Application

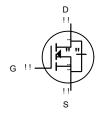
Battery protection

Load switch

Uninterruptible power supply



DFN5X6-8L (TDSON-8)



N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
NVMFS5C670NLWFAFT3G	DFN5X6-8L(TDSON-8)	HXY MOSFET	5000

Absolute Maximum Ratings (T_C=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units		
Vps	Drain-Source Voltage	60	V		
Vgs	Gate-Source Voltage	V			
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	ontinuous Drain Current, V _{GS} @ 10V ¹ 80			
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	52	А		
Ірм	Pulsed Drain Current ²	320	А		
EAS	Single Pulse Avalanche Energy ³	169	mJ		
P _D @T _C =25°C	Total Power Dissipation ⁴	Total Power Dissipation ⁴ 108			
Тѕтс	Storage Temperature Range	-55 to 150	°C		
TJ	Operating Junction Temperature Range	ing Junction Temperature Range -55 to 150			
Reлc	Rejc Thermal Resistance Junction-Case ¹		°C/W		

N-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_J=25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
Off Charac	cteristic	,			'	
V _{(BR)D} s	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	60	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =60V, V _{GS} =0V,	-	-	1.0	μA
I_{GSS}	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} =±20V	-	-	±100	nA
On Claract	eristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	2	3	4	V
R _{DS(on)}	Static Drain-Source on-Resistance	V _{GS} =10V, I _D = 30A - 1			7	mΩ
Dynamic C	Characteristics					
C _{iss}	Input Capacitance	V _{DS} =30V,	-	4136	-	pF
Coss	Output Capacitance	V _{GS} =0V,	-	286	-	pF
C _{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	257	-	pF
Qg	Total Gate Charge	\/ -20\/	-	90	-	nC
Q_{gs}	Gate-Source Charge	V _{DS} =30V, I _D =30A, V _{GS} =10V	-	9	-	nC
Q_gd	Gate-Drain("Miller") Charge	1D-30A, VGS-10V	-	18	-	nC
Switching	Characteristics					
t _{d(on)}	Turn-on Delay Time		-	9	-	ns
t _r	Turn-on Rise Time	V _{DS} =30V, I _D =30A,	-	7	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	R _G =1.8Ω, V _{GS} =10V	-	40	-	ns
t _f	Turn-off Fall Time		-	15	-	ns
DrainSour	ce Diode Characteristics and Maximu	ım Ratings				
Is	Maximum Continuous Drain to Source Diode Forward Current			-	80	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current			-	320	Α
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} =0VI _S =30A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time		-	33	-	ns
Qrr	Body Diode Reverse Recovery Charge	I _F =30A, dI/dt=100A/μs	-	46	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

^{2.} EAS condition : T_J =25°C, V_{DD} =30V, V_G =10V, L=0.5mH, Rg=25 Ω , I_{AS} =26A

^{3.} Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%

Typical Performance Characteristics

Figure1: Output Characteristics

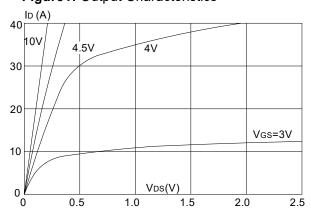


Figure 2: Typical Transfer Characteristics

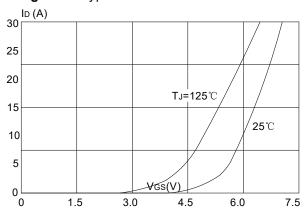


Figure 3:On-resistance vs. Drain Current

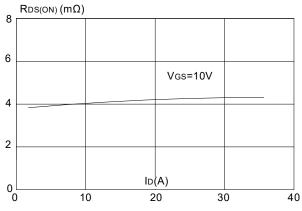


Figure 4: Body Diode Characteristics

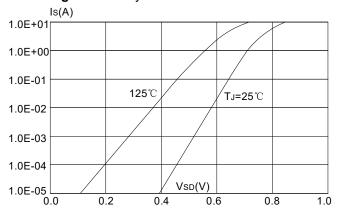


Figure 5: Gate Charge Characteristics

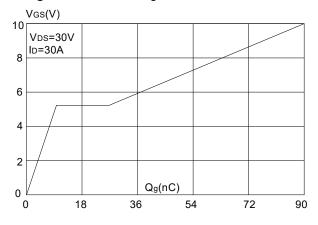
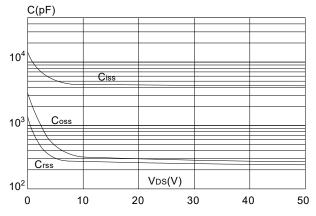


Figure 6: Capacitance Characteristics



N-Channel Enhancement Mode MOSFET

Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

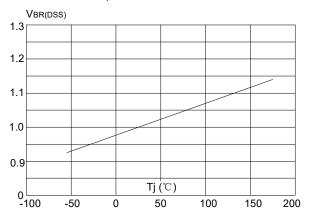


Figure 9: Maximum Safe Operating Area

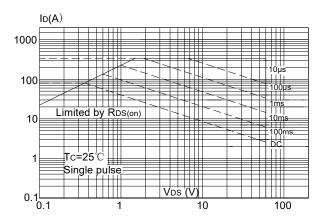


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

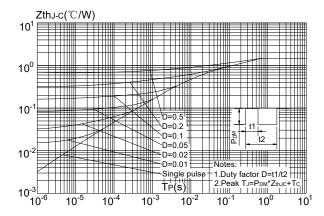


Figure 8: Normalized on Resistance vs. Junction Temperature

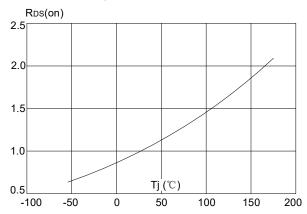
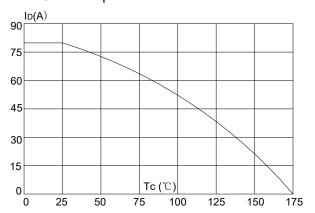
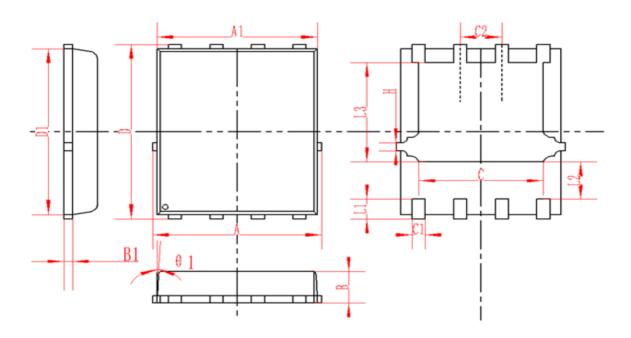


Figure 10: Maximum Continuous Drain Current vs. Case Temperature





DFN5X6-8L(TDSON-8) Package Information



SYMBOL	MM		INCH			
STIVIDOL	MIN	NOM	MAX	MIN	NOM	MAX
А	4.95	5	5.05	0.195	0.197	0.199
A1	4.82	4.9	4.98	0.190	0.193	0.196
D	5.98	6	6.02	0.235	0.236	0.237
D1	5.67	5.75	5.83	0.223	0.226	0.230
В	0.9	0.95	1	0.035	0.037	0.039
B1	0.254REF		0.010REF			
С	3.95	4	4.05	0.156	0.157	0.159
C1	0.35	0.4	0.45	0.014	0.016	0.018
C2		1.27TYP			0.5TYP	
θ1	8°	10°	12°	8°	10°	12°
L1	0.63	0.64	0.65	0.025	0.025	0.026
L2	1.2	1.3	1.4	0.047	0.051	0.055
L3	3.415	3.42	3.425	0.134	0.135	0.135
Н	0.24	0.25	0.26	0.009	0.010	0.010

N-Channel Enhancement Mode MOSFET

Attention

- Any and all HUA XUAN YANG ELECTRONICS products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your HUA XUAN YANG ELECTRONICS representative nearest you before using any HUA XUAN YANG ELECTRONICS products described or contained herein in such applications.
- HUA XUAN YANG ELECTRONICS assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all HUA XUAN YANG ELECTRONICS products described or contained herein.
- Specifications of any and all HUA XUAN YANG ELECTRONICS products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- HUA XUAN YANG ELECTRONICS CO.,LTD. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- In the event that any or all HUA XUAN YANG ELECTRONICS products(including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of HUA XUAN YANG ELECTRONICS CO.,LTD.
- Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production.

 HUA XUAN YANG ELECTRONICS believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc.

 When designing equipment, refer to the "Delivery Specification" for the HUA XUAN YANG ELECTRONICS product that you intend to use.